BUK9528-55

GENERAL DESCRIPTION

N-channel enhancement mode logic level field-effect power transistor in a plastic envelope using 'trench' technology. The device features very low on-state resistance and has integral zener diodes giving ESD protection up to 2kV. It is intended for use in automotive and general purpose switching applications.

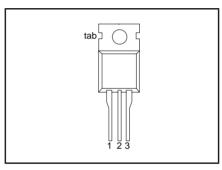
QUICK REFERENCE DATA

SYMBOL	PARAMETER	MAX.	UNIT
V _{DS} I _D P _{tot} T _j R _{DS(ON)}	Drain-source voltage Drain current (DC) Total power dissipation Junction temperature Drain-source on-state resistance $V_{GS} = 5 \text{ V}$	55 40 96 175 28	V A W °C mΩ

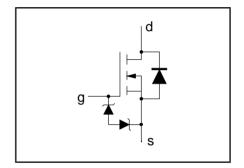
PINNING - TO220AB

PIN	DESCRIPTION	
1	gate	
2	drain	
3	source	
tab	drain	

PIN CONFIGURATION



SYMBOL



LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System (IEC 134)

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_{DS}	Drain-source voltage	-	-	55	V
V_{DGR}	Drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$	-	55	V
±V _{GS}	Gate-source voltage	-	-	10	V
I _D	Drain current (DC)	$T_{mb} = 25 ^{\circ}C$	-	40	Α
I _D	Drain current (DC)	$T_{mb} = 100 ^{\circ}C$	-	28	Α
I _{DM}	Drain current (pulse peak value)	$T_{mb} = 25 ^{\circ}C$	-	160	Α
P _{tot}	Total power dissipation	$T_{mb} = 25 ^{\circ}C$	-	96	W
T_{stg}^{red},T_{j}	Storage & operating temperature	-	- 55	175	°C

ESD LIMITING VALUE

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V _C	Electrostatic discharge capacitor voltage, all pins	Human body model (100 pF, 1.5 kΩ)	-	2	kV

THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	TYP.	MAX.	UNIT
R _{th j-mb}	Thermal resistance junction to mounting base	-	-	1.56	K/W
R _{th j-a}	Thermal resistance junction to ambient	in free air	60	-	K/W

Philips Semiconductors Product specification

TrenchMOS™ transistor Logic level FET

BUK9528-55

STATIC CHARACTERISTICS

T_i= 25°C unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
V _{(BR)DSS}	Drain-source breakdown	$V_{GS} = 0 \text{ V}; I_D = 0.25 \text{ mA};$	55	-	-	V
	voltage	$T_i = -55^{\circ}C$	50	-	-	V
$V_{GS(TO)}$	Gate threshold voltage	$V_{DS} = V_{GS}$; $I_D = 1 \text{ mA}$	1	1.5	2	V
33(13)		$T_j = 175^{\circ}C$ $T_i = -55^{\circ}C$	0.5	-	-	V
		$T_i = -55^{\circ}C$	-	-	2.3	
I _{DSS}	Zero gate voltage drain current	$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V};$	-	0.05	10	μΑ
		T _i = 175°C	-	-	500	μA
I _{GSS}	Gate source leakage current	$V_{GS} = \pm 5 \text{ V}; V_{DS} = 0 \text{ V}$	-	0.02	1	μA
		T _i = 175°C	-		10	μA
±V _{(BR)GSS}	Gate-source breakdown	$I_G = \pm 1 \text{ mA};$	10	-	-	٠̈V
(=:1)	voltage					
R _{DS(ON)}	Drain-source on-state	$V_{GS} = 5 \text{ V}; I_D = 20 \text{ A}$	-	22	28	mΩ
23(311)	resistance	$T_j = 175^{\circ}C$	-	-	59	mΩ

DYNAMIC CHARACTERISTICS

 $T_{mb} = 25^{\circ}C$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
g _{fs}	Forward transconductance	$V_{DS} = 25 \text{ V}; I_{D} = 25 \text{ A}$	13	-	-	S
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Feedback capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz}$	-	1300 250 130	1700 300 180	pF pF pF
$egin{array}{c} t_{d\ on} \\ t_{r} \\ t_{d\ off} \\ t_{f} \end{array}$	Turn-on delay time Turn-on rise time Turn-off delay time Turn-off fall time	V_{DD} = 30 V; I_{D} = 25 A; V_{GS} = 5 V; R_{G} = 10 Ω Resistive load	- - - -	22 85 70 64	32 125 95 85	ns ns ns ns
L _d	Internal drain inductance Internal drain inductance	Measured from contact screw on tab to centre of die Measured from drain lead 6 mm from package to centre of die	-	3.5 4.5	-	nH nH
L _s	Internal source inductance	Measured from source lead 6 mm from package to source bond pad	-	7.5	-	nΗ

REVERSE DIODE LIMITING VALUES AND CHARACTERISTICS

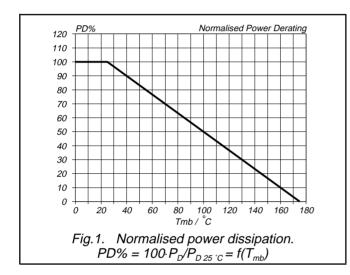
 $T_i = 25^{\circ}C$ unless otherwise specified

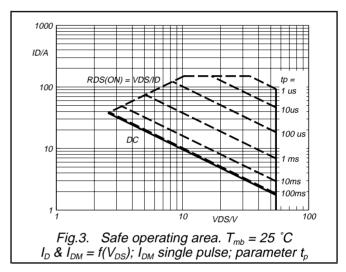
SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
I _{DR}	Continuous reverse drain current		-	-	40	Α
I _{DRM}	Pulsed reverse drain current		-	-	160	Α
V_{SD}	Diode forward voltage	$I_F = 25 \text{ A}; V_{GS} = 0 \text{ V}$ $I_F = 40 \text{ A}; V_{GS} = 0 \text{ V}$	-	0.95	1.2	V
		$I_F = 40 \text{ A}; V_{GS} = 0 \text{ V}$	-	1.0	-	
t _{rr}	Reverse recovery time	$I_F = 40 \text{ A}$; $-dI_F/dt = 100 \text{ A/}\mu\text{s}$;	-	41	-	ns
\ddot{Q}_{rr}	Reverse recovery charge	$V_{GS} = -10 \text{ V}; V_{R} = 30 \text{ V}$	-	0.16	-	μC

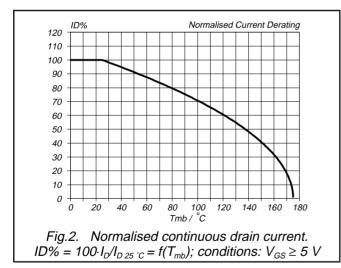
BUK9528-55

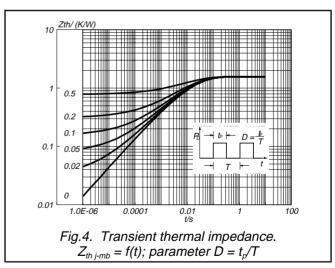
AVALANCHE LIMITING VALUE

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
W _{DSS}		$I_D = 35 \text{ A}; V_{DD} \le 25 \text{ V};$ $V_{GS} = 5 \text{ V}; R_{GS} = 50 \Omega; T_{mb} = 25 \text{ °C}$	-	-	70	mJ

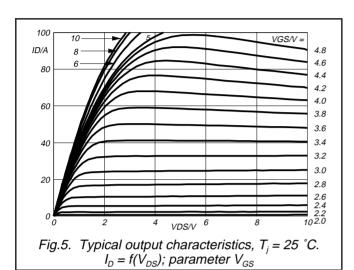


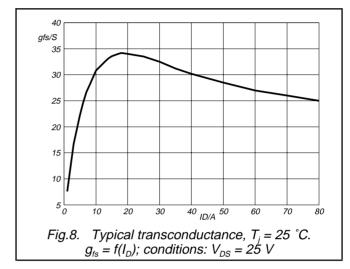


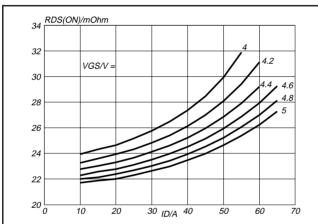


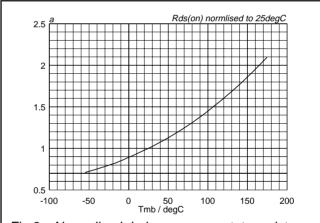


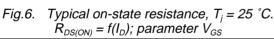
BUK9528-55

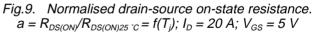


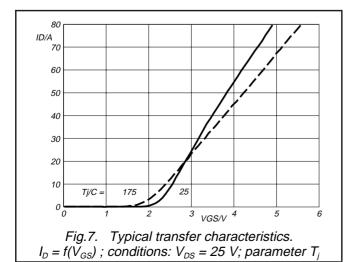












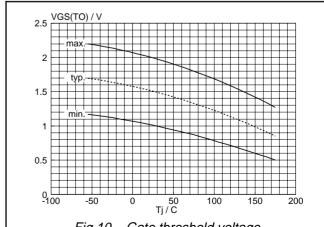
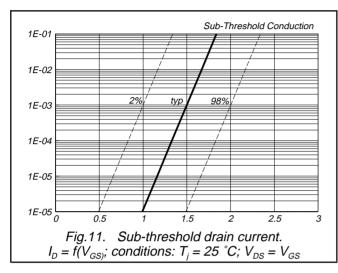
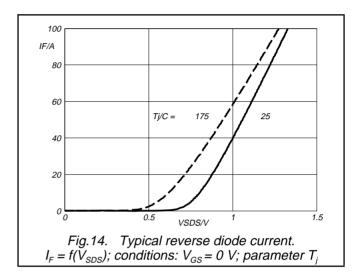
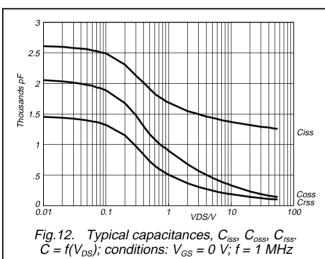


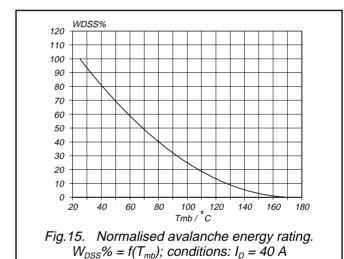
Fig.10. Gate threshold voltage. $V_{GS(TO)} = f(T_j)$; conditions: $I_D = 1$ mA; $V_{DS} = V_{GS}$

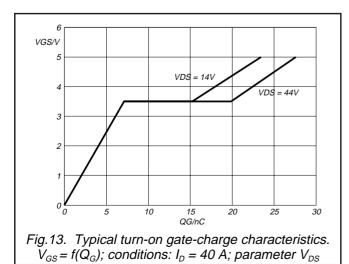
BUK9528-55

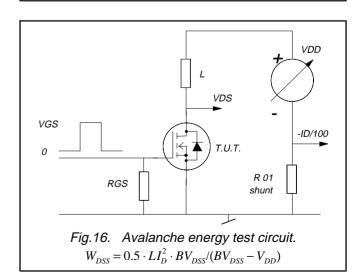




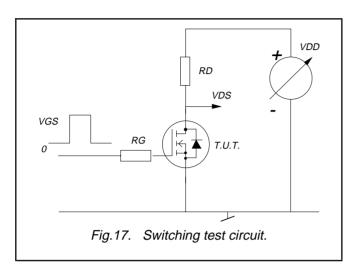






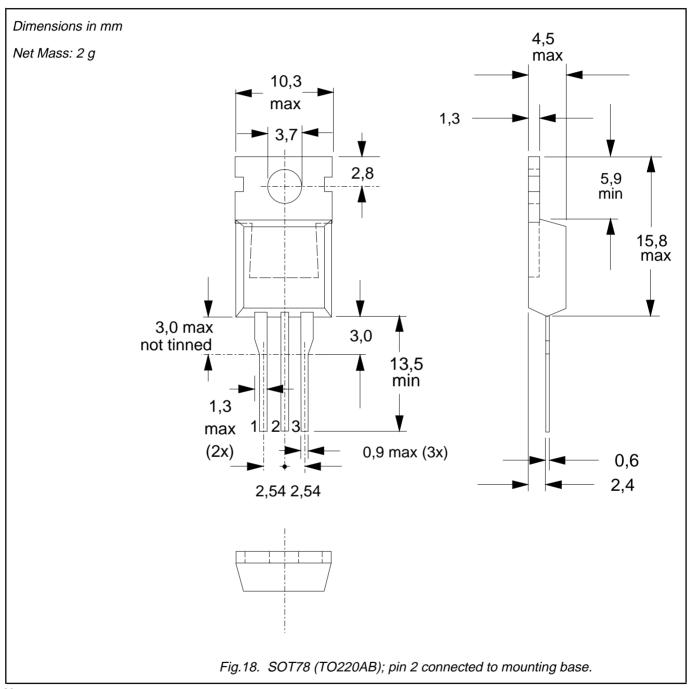


BUK9528-55



BUK9528-55

MECHANICAL DATA



Notes

- 1. Observe the general handling precautions for electrostatic-discharge sensitive devices (ESDs) to prevent damage to MOS gate oxide.
- 2. Refer to mounting instructions for SOT78 (TO220) envelopes.
- 3. Epoxy meets UL94 V0 at 1/8".

Philips Semiconductors Product specification

TrenchMOS™ transistor Logic level FET

BUK9528-55

DEFINITIONS

Data sheet status				
Objective specification	This data sheet contains target or goal specifications for product development.			
Preliminary specification	This data sheet contains preliminary data; supplementary data may be published later.			
Product specification	This data sheet contains final product specifications.			
Limiting values				

Limiting values are given in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of this specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

Application information

Where application information is given, it is advisory and does not form part of the specification.

© Philips Electronics N.V. 1997

All rights are reserved. Reproduction in whole or in part is prohibited without the prior written consent of the copyright owner.

The information presented in this document does not form part of any quotation or contract, it is believed to be accurate and reliable and may be changed without notice. No liability will be accepted by the publisher for any consequence of its use. Publication thereof does not convey nor imply any license under patent or other industrial or intellectual property rights.

LIFE SUPPORT APPLICATIONS

These products are not designed for use in life support appliances, devices or systems where malfunction of these products can be reasonably expected to result in personal injury. Philips customers using or selling these products for use in such applications do so at their own risk and agree to fully indemnify Philips for any damages resulting from such improper use or sale.